

# ELT 225 : Characterization, Testing of Nanofabricated Structures and Materials

This course examines a variety of techniques and measurements essential for testing and for controlling material fabrication and final device performance. Characterization includes electrical, optical, physical, and chemical approaches. The characterization experience will include hands-on use of tools such as the Atomic Force Microscope (AFM), Scanning Electron Microscope (SEM), fluorescence microscopes, and fourier transform infrared spectroscopy.

**Credits** 3

**Notes**

Course offered on the Penn State University Campus in partnership with the Penn State University Nanotechnology Program.